

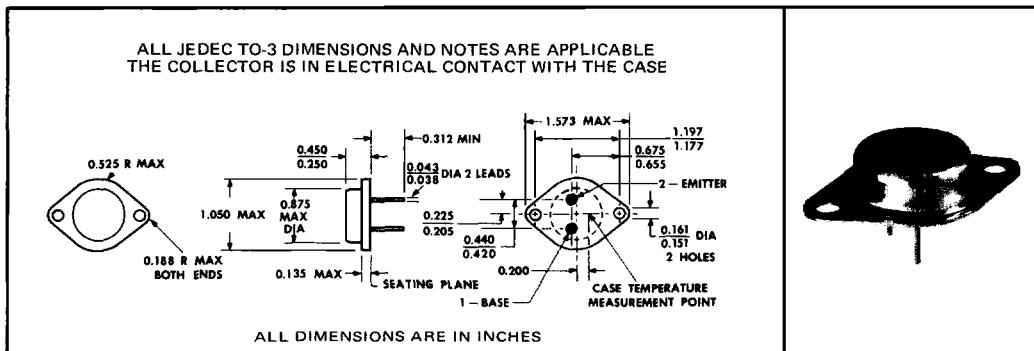
# TYPES 2N5869, 2N5870

## N-P-N SINGLE-DIFFUSED SILICON POWER TRANSISTORS

**FOR POWER-AMPLIFIER AND HIGH-SPEED-SWITCHING APPLICATIONS  
DESIGNED FOR COMPLEMENTARY USE WITH 2N5867, 2N5868**

- 87.5 Watts at 25°C Case Temperature
- 5-A Rated Continuous Collector Current
- Min  $f_T$  of 4 MHz at 10 V, 0.25 A
- 62.5-mJ Reverse Energy Rating

\*mechanical data



absolute maximum ratings at 25°C case temperature (unless otherwise noted)

	2N5869	2N5870
Collector-Base Voltage	60 V*	80 V*
Collector-Emitter Voltage (See Note 1)	60 V*	80 V*
Emitter-Base Voltage	5 V*	5 V*
Continuous Collector Current	{ 5 A† 3 A*}	7 A
Peak Collector Current (See Note 2)	3 A*	1 A*
Continuous Base Current	1 A*	See Figure 1
Safe Operating Area at (or below) 25°C Case Temperature	87.5 W*	87.5 W*
Continuous Device Dissipation at (or below) 25°C Case Temperature (See Note 3)	5 W	5 W
Continuous Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 4)	62.5 mJ	62.5 mJ
Unclamped Inductive Load Energy (See Note 5)	-65°C to 200°C*	-65°C to 200°C*
Operating Collector Junction Temperature Range	-250°C*	-250°C*
Storage Temperature Range	-250°C*	-250°C*
Terminal Temperature 1/16 Inch from Case for 10 Seconds	-250°C*	-250°C*

- NOTES:
1. These values apply when the base-emitter diode is open-circuited.
  2. This value applies for  $t_{sw} \leq 1$  ms, duty cycle  $\leq 10\%$ .
  3. Derate linearly to 200°C case temperature at the rate of 0.5 mW/°C.
  4. Derate linearly to 200°C free-air temperature at the rate of 28.6 mW/°C.
  5. This rating is based on the capability of the transistors to operate safely in the unclamped-inductive load circuit of Section 3.2 of the forthcoming JEDEC publication *Suggested Standards on Power Transistors*.<sup>‡</sup>  $L = 20$  mH,  $R_{BB1} = 20 \Omega$ ,  $R_{BB2} = 100 \Omega$ ,  $V_{BB1} = 10$  V,  $V_{BB2} = 0$  V,  $R_L = 0.1 \Omega$ ,  $V_{CC} = 10$  V,  $I_{CM} = 2.5$  A. Energy  $\approx I_C^2 L / 2$ .

\* JEDEC registered data. This data sheet contains all applicable registered data in effect at the time of publication.

† Texas Instruments guarantees this value in addition to the JEDEC registered value which is also shown.

‡ This circuit appears on page 5-1 of this data book.

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# TYPES 2N5869, 2N5870

## N-P-N SINGLE-DIFFUSED SILICON POWER TRANSISTORS

\*electrical characteristics at 25°C case temperature (unless otherwise noted)

PARAMETER	TEST CONDITIONS			2N5869	2N5870	UNIT
				MIN	MAX	
$V_{(BR)CEO}$ Collector-Emitter Breakdown Voltage	$I_C = 100 \text{ mA}$ , $I_B = 0$ , See Note 6			60	80	V
$I_{CEO}$ Collector Cutoff Current	$V_{CE} = 30 \text{ V}$ , $I_B = 0$			0.5		mA
	$V_{CE} = 40 \text{ V}$ , $I_B = 0$				0.5	
	$V_{CE} = 60 \text{ V}$ , $V_{BE} = -1.5 \text{ V}$			0.1		
	$V_{CE} = 80 \text{ V}$ , $V_{BE} = -1.5 \text{ V}$				0.1	
	$V_{CE} = 60 \text{ V}$ , $V_{BE} = -1.5 \text{ V}$ , $T_C = 150^\circ\text{C}$			2		
	$V_{CE} = 80 \text{ V}$ , $V_{BE} = -1.5 \text{ V}$ , $T_C = 150^\circ\text{C}$				2	
$I_{CBO}$ Collector Cutoff Current	$V_{CB} = 60 \text{ V}$ , $I_E = 0$			0.1		mA
	$V_{CB} = 80 \text{ V}$ , $I_E = 0$				0.1	
$I_{EBO}$ Emitter Cutoff Current	$V_{EB} = 5 \text{ V}$ , $I_C = 0$			1	1	mA
	$V_{CE} = 4 \text{ V}$ , $I_C = 300 \text{ mA}$	See Notes 6 and 7		35	35	
$hFE$ Static Forward Current Transfer Ratio	$V_{CE} = 4 \text{ V}$ , $I_C = 1.5 \text{ A}$			20	100	20
	$V_{CE} = 4 \text{ V}$ , $I_C = 3 \text{ A}$			5	5	100
$V_{BE}$ Base-Emitter Voltage	$I_B = 200 \text{ mA}$ , $I_C = 2 \text{ A}$	See Notes 6 and 7		1.6	1.6	V
	$V_{CE} = 4 \text{ V}$ , $I_C = 3 \text{ A}$			2	2	
$V_{CE(sat)}$ Collector-Emitter Saturation Voltage	$I_B = 200 \text{ mA}$ , $I_C = 2 \text{ A}$	See Notes 6 and 7		1	1	V
	$I_B = 0.6 \text{ A}$ , $I_C = 3 \text{ A}$			2	2	
$h_{fe}$ Small-Signal Common-Emitter Forward Current Transfer Ratio	$V_{CE} = 4 \text{ V}$ , $I_C = 0.25 \text{ A}$ , $f = 1 \text{ kHz}$			20	20	
$ h_{fe} $ Small-Signal Common-Emitter Forward Current Transfer Ratio	$V_{CE} = 10 \text{ V}$ , $I_C = 0.25 \text{ A}$ , $f = 1 \text{ MHz}$			4	4	
Cobo Common-Base Open-Circuit Output Capacitance	$V_{CB} = 10 \text{ V}$ , $I_E = 0$ , $f = 1 \text{ MHz}$			150	150	pF

NOTES: 6. These parameters must be measured using pulse techniques.  $t_w = 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .

7. These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts and located within 0.125 inch from the device body.

\*switching characteristics at 25°C case temperature

PARAMETER	TEST CONDITIONS†			MIN	MAX	UNIT
$t_r$ Rise Time	$I_C = 1.5 \text{ A}$ ,	$I_B(1) = 0.15 \text{ A}$ ,	$I_B(2) = -0.15 \text{ A}$ ,		0.7	
$t_s$ Storage Time		$V_{BE(\text{off})} = -5 \text{ V}$ ,	$R_L = 20 \Omega$ ,		1	μs
$t_f$ Fall Time			See Note 8		0.8	

†Voltage and current values shown are nominal; exact values vary slightly with transistor parameters.

\*JEDEC registered data.

NOTE 8: These characteristics are measured in the circuit of clause 3.3.13.2 of the forthcoming JEDEC publication *Suggested Standards on Power Transistors*. ‡  $V_{BB1} = 25 \text{ V}$ ,  $V_{BB2} = 5 \text{ V}$ ,  $V_{CC} = 30 \text{ V}$ ,  $V_{on} = 23 \text{ V}$ ,  $R_{BB1} = 73 \Omega$ ,  $R_{BB2} = 39 \Omega$ .

‡This circuit appears on page 5-1 of this data book.

### MAXIMUM SAFE OPERATING AREA

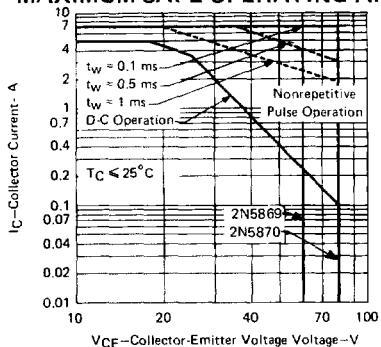


FIGURE 1

### THERMAL CHARACTERISTICS

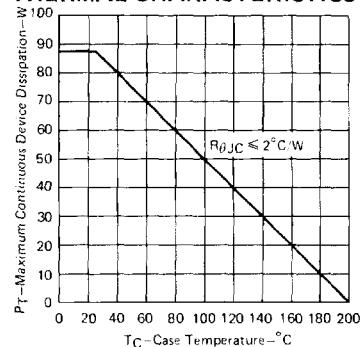


FIGURE 2